

Notice of References Cited	Application/Control No. 10/542,250		Applicant(s)/Patent Under Reexamination TERANISHI ET AL.	
	Examiner Emmanuel Hailemariam		Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,377,098	04-2002	Rebeor, Chris J.	327/210
*	B	US-5,724,061	03-1998	Kanbara, Minoru	345/100
*	C	US-6,008,801	12-1999	Jeong, Kwoan-Yel	345/204
*	D	US-6,664,943	12-2003	Nakajima et al.	345/98
*	E	US-6,208,170	03-2001	Iwaki et al.	326/121
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1014334 A2	06-2000	European Patent	NAKAJIMA et al.	G09G 3/36
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.